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[Indexation and Incomes Policy: A Study of Wage Adjustment in Unionized Manufacturing](#) - all 3 versions »

SG Cecchetti - Journal of Labor Economics, 1987 - JSTOR

 ... How. Wage Adjustments in Unionized **Manufacturing** 397 good a ... as a result of staggered **adjustment** and long ... contracts have the opportunity to **adjust** their nominal ...

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[Method of making single-step trenches using resist fill and recess](#) - all 2 versions »

KM Golden, PH Pan, KJ Stewart, AC Thomas - US Patent 5,618,751, 1997 - Google Patents

 ... reflowing the resist which also serves to **adjust** exposure sensitivity ... is substantially otherwise complete; reducing not only **manufacturing yield** but increasing ...

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[Method for efficient manufacturing of integrated circuits](#) - all 4 versions »

L Breiner, RPS Thakur - US Patent 6,526,547, 2003 - Google Patents

 ... of the new process and **adjusting** process variables of ... go process parameters chosen for **adjustment** will be ... to significantly affect the **manufacturing** process and ...

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[Control Policy for a Manufacturing System with Random Yield and Rework](#) - all 4 versions »

L Gong, H Matsuo - Journal of Optimization Theory and Applications, 1997 - Springer

 ... However, in IC chip **manufacturing**, since many chips are ... and (11), and from the independence of **yield** and rework ... actually implemented, we may need to **adjust**  $x(t)$  ...

[Cited by 19](#) - [Related Articles](#) - [Web Search](#)
[Automation manufacturing systems technology for opto-electronic device packaging](#)

S Jang - Electronic Components and Technology Conference, 2000. 2000 ..., 2000 - ieeexplore.ieee.org

 ... **manufacturing** cost reduction and **yield** improvement, several ... the various phases of the **manufacturing** line ... automated post-weld fiber **adjustment** capabilities will ...

[Cited by 30](#) - [Related Articles](#) - [Web Search](#)
[An agenda for research on the flexibility of manufacturing processes](#) - all 3 versions »

D Gerwin - International Journal of Operations and Production ..., 1987 - emeraldinsight.com

 ... Material flexibility exists when there are **adjustment** mechanisms at one ... can locate bent metal and either **adjust** it or ... Flexibility of **manufacturing** processes ...

[Cited by 174](#) - [Related Articles](#) - [Web Search](#)
[The dynamics of industrial concentration in Australian manufacturing](#) - all 7 versions »

M Bhattacharya, H Bloch - International Journal of Industrial Organization, 2000 - Elsevier

 ... is under less pressure to **adjust** to disequilibrium. ... indicate an annual speed of **adjustment** of about 1%. Studies of British **manufacturing yield** somewhat higher ...

[Cited by 20](#) - [Related Articles](#) - [Web Search](#) - [Library Search](#)
[Method and apparatus for yield and failure analysis in the manufacturing of semiconductors](#) -

[all 3 versions »](#)

JR Lovelace - US Patent 6,477,685, 2002 - Google Patents

... ADJUST YAXIS V i ADJUST XAXIS ... Page 13. US 6,477,685 BI METHOD AND APPARATUS FOR YIELD

AND FAILURE ANALYSIS IN THE **MANUFACTURING** OF SEMICONDUCTORS ...

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[Externalising Abstract Mathematical Models](#) - [all 5 versions »](#)

L Tweedie, R Spence, H Dawkes, H Su - portal.acm.org

... Design proceeds through the gradual **adjustment** of parameters ... the user needs to **adjust** the tolerances ... perhaps even trading off **manufacturing yield** against cost. ...

[Cited by 73](#) - [Related Articles](#) - [Web Search](#)

[Delay Testing Quality in Timing-Optimized Designs](#) - [all 3 versions »](#)

ES Park, B Underwood, TW Williams, MR Mercer - Test Conference, 1991, Proceedings., International, 1991 - [ieeexplore.ieee.org](#)

... will increasingly refine delay measurements and **adjust** path delays so ... can be done through the **adjustment** of either ... on the **yield** of a **manufacturing** process and ...

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